



**Reliability Report  
(Q2017-006)**

**CPC7514Z Product Reliability Monitor  
Quad High Voltage Isolated Analog Switch Array**

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**IXYS Integrated Circuits Division  
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**Summary**

The CPC7514Z product has successfully passed IXYS ICD's requirements for product qualification.

**Table 1: Device Information**

Product Number	CPC7514Z
Package Type	20 Pin SOIC
Assembly Site	Atec, Laguna, Philippines
Test Site	IXYS ICD BEV, Beverly, MA, USA

**Table 2: Reliability Test Result**

Stress Test	Stress Conditions	Applicable Specs	Product/Package	Sample Size (SS)	# of Failures
HAST	130C,85%, 18.8psi,96hrs	JESD22-A110-C	CPC7514Z T66854	77	0
Thermal Shock	0 to 100°C, 10/10 dwells, 15 cycles	Mil-Std-883, M1011	CPC7514Z T66854	55	0
Temperature Cycle	-55 to 125°C, 10/10 dwells, 300 cycles	Mil-Std-883, M1010, "B"	CPC7514Z T66854	55	0
Hot Storage	125C, 1000 hrs	JESD22-A103-C	CPC7514Z T66854	50	0
MSL	IR Reflow, Level 1	J-STD-020D.1	CPC7514Z T66854	25	0

**Table 3: FIT Rate Summary**

Qual Lot #	Stress Test	# of Devices	# of Fail	Hours Tested	Equivalent Dev. Hours	FIT Rate @ 60% CL
1	HAST	77	0	96	10,583,759	86.93*

\*HAST FIT Rate was calculated based on the Acceleration Factor (AF) and equivalent device hours at 0.7eV of activation energy at 125°C test temperature and 40°C use temperature.

**Approvals**

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